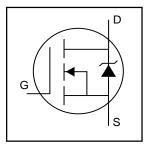
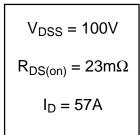
International Rectifier

IRF3710

HEXFET® Power MOSFET

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated





Description

Advanced HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.



Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	57	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	40	Α
I _{DM}	Pulsed Drain Current ①	230	
P _D @T _C = 25°C	Power Dissipation	200	W
	Linear Derating Factor	1.3	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
I _{AR}	Avalanche Current①	28	А
E _{AR}	Repetitive Avalanche Energy①	20	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.8	V/ns
T _J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		0.75	
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Parameter	Min.	Тур.	Max.	Units	Conditions
Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$
Breakdown Voltage Temp. Coefficient		0.13		V/°C	Reference to 25°C, I _D = 1mA
Static Drain-to-Source On-Resistance			23	mΩ	V _{GS} = 10V, I _D =28A ④
Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
Forward Transconductance	32			S	V _{DS} = 25V, I _D = 28A⊕
Drain-to-Source Leakage Current			25	μА	V _{DS} = 100V, V _{GS} = 0V
			250		$V_{DS} = 80V, V_{GS} = 0V, T_{J} = 150$ °C
Gate-to-Source Forward Leakage			100	nΛ	V _{GS} = 20V
Gate-to-Source Reverse Leakage			-100	111/4	V _{GS} = -20V
Total Gate Charge			130		I _D = 28A
Gate-to-Source Charge			26	nC	$V_{DS} = 80V$
Gate-to-Drain ("Miller") Charge			43		V_{GS} = 10V, See Fig. 6 and 13
Turn-On Delay Time		12			V _{DD} = 50V
Rise Time		58		nc	$I_D = 28A$
Turn-Off Delay Time		45		115	$R_G = 2.5\Omega$
Fall Time		47			V _{GS} = 10V, See Fig. 10 ④
Internal Drain Industance		15			Between lead,
Internal Drain Inductance		4.5		الم	6mm (0.25in.)
Internal Source Inductance		7.5		11111	from package
					and center of die contact
Input Capacitance		3130			V _{GS} = 0V
Output Capacitance	_	410			$V_{DS} = 25V$
Reverse Transfer Capacitance		72		pF	f = 1.0MHz, See Fig. 5
Single Pulse Avalanche Energy2		1060 ଓ	280©	mJ	I _{AS} = 28A, L = 0.70mH
	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Input Capacitance Output Capacitance Reverse Transfer Capacitance	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Input Capacitance Output Capacitance ———————————————————————————————————	Drain-to-Source Breakdown Voltage 100 — Breakdown Voltage Temp. Coefficient — 0.13 Static Drain-to-Source On-Resistance — — Gate Threshold Voltage 2.0 — Forward Transconductance 32 — Drain-to-Source Leakage Current — — Gate-to-Source Forward Leakage — — Gate-to-Source Reverse Leakage — — Total Gate Charge — — Gate-to-Source Charge — — Gate-to-Drain ("Miller") Charge — — Turn-On Delay Time — 12 Rise Time — 45 Turn-Off Delay Time — 47 Internal Drain Inductance — 4.5 Internal Source Inductance — 7.5 Input Capacitance — 3130 Output Capacitance — 410 Reverse Transfer Capacitance — 72	Drain-to-Source Breakdown Voltage 100 — — Breakdown Voltage Temp. Coefficient — 0.13 — Static Drain-to-Source On-Resistance — 23 Gate Threshold Voltage 2.0 — 4.0 Forward Transconductance 32 — — Drain-to-Source Leakage Current — 25 — — 250 Gate-to-Source Forward Leakage — — 100 — — 25 — — 250 Gate-to-Source Reverse Leakage — — 100 — — 100 _ _ — 100 _ _ _ _ _ 100 _	Drain-to-Source Breakdown Voltage 100 — V Breakdown Voltage Temp. Coefficient — 0.13 — V/°C Static Drain-to-Source On-Resistance — 23 mΩ Gate Threshold Voltage 2.0 — 4.0 V Forward Transconductance 32 — — S Drain-to-Source Leakage Current — — 25 μA Gate-to-Source Forward Leakage — — 100 nA Gate-to-Source Reverse Leakage — — 130 nA Gate-to-Source Charge — — 130 nC Gate-to-Drain ("Miller") Charge — — 43 T Turn-On Delay Time — 12 — nS Fall Time — 45 — nS Internal Drain Inductance — 4.5 — nH Internal Source Inductance — 3130 — nH Internal Capacitance — 410

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions			
Is	Continuous Source Current			F.7		MOSFET symbol			
	(Body Diode)		57	57	A	showing the			
I _{SM}	Pulsed Source Current			2	220	220	230	, ,	integral reverse
	(Body Diode)①				23	230		230	230
V_{SD}	Diode Forward Voltage			1.2	V	$T_J = 25^{\circ}C$, $I_S = 28A$, $V_{GS} = 0V$ ④			
t _{rr}	Reverse Recovery Time		140	220	ns	$T_J = 25$ °C, $I_F = 28A$			
Q _{rr}	Reverse Recovery Charge		670	1010	nC	di/dt = 100A/µs ④			
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)							

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $\label{eq:starting} \begin{array}{ll} \text{ Starting T}_J = 25^{\circ}\text{C}, \ L = 0.70\text{mH} \\ \text{R}_G = 25\Omega, \ \text{I}_{AS} = 28\text{A}, \ \text{V}_{GS} = 10\text{V (See Figure 12)} \\ \end{array}$
- $\label{eq:loss_def} \begin{tabular}{ll} $I_{SD} \leq 28A, \ di/dt \leq 380A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \\ $T_J \leq 175^{\circ}C$ \end{tabular}$
- 4 Pulse width \leq 400 μ s; duty cycle \leq 2%.
- ⑤ This is a typical value at device destruction and represents operation outside rated limits.
- 6 This is a calculated value limited to $T_J = 175^{\circ}C$.

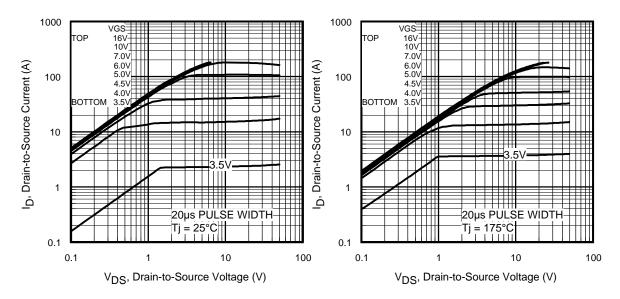


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics

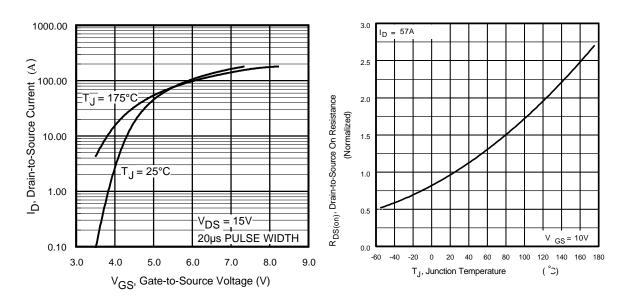


Fig 3. Typical Transfer Characteristics

Fig 4. Normalized On-Resistance Vs. Temperature

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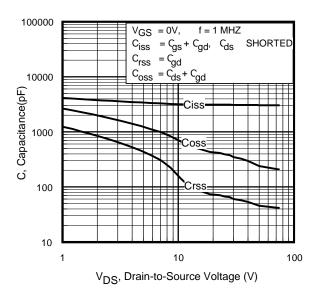


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

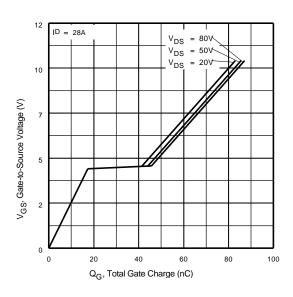


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

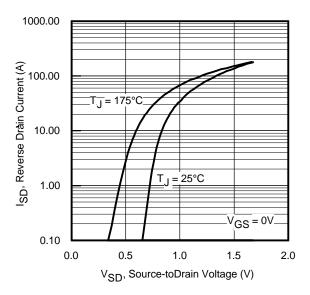


Fig 7. Typical Source-Drain Diode Forward Voltage

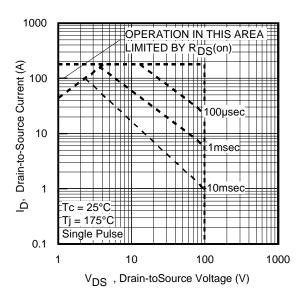


Fig 8. Maximum Safe Operating Area

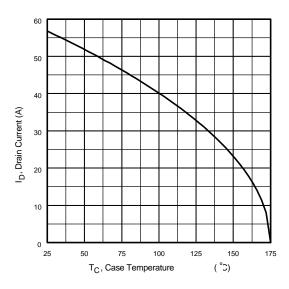


Fig 9. Maximum Drain Current Vs. Case Temperature

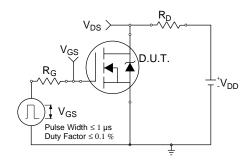


Fig 10a. Switching Time Test Circuit

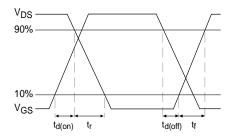


Fig 10b. Switching Time Waveforms

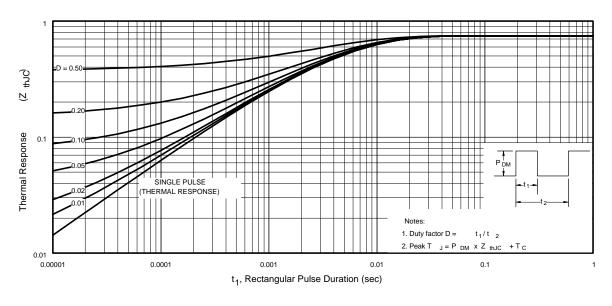


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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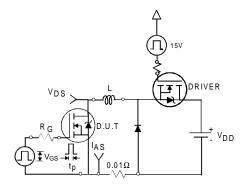


Fig 12a. Unclamped Inductive Test Circuit

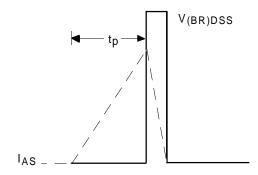


Fig 12b. Unclamped Inductive Waveforms

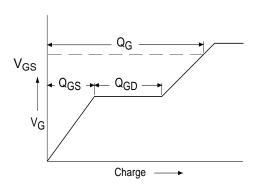


Fig 13a. Basic Gate Charge Waveform

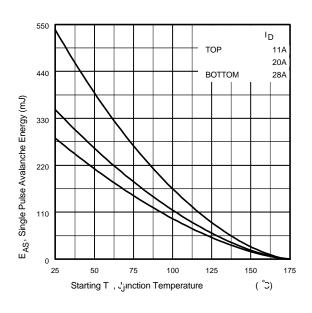


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

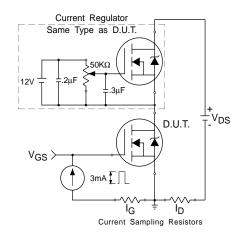
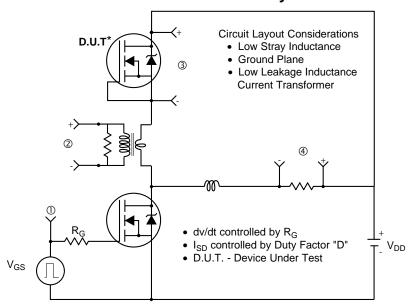


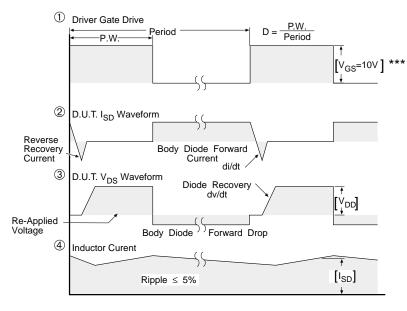
Fig 13b. Gate Charge Test Circuit

7

Peak Diode Recovery dv/dt Test Circuit



* Reverse Polarity of D.U.T for P-Channel



*** $V_{GS} = 5.0V$ for Logic Level and 3V Drive Devices

Fig 14. For N-channel HEXFET® power MOSFETs

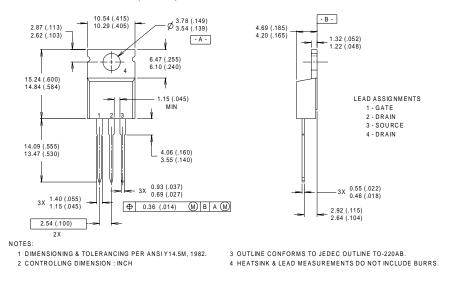
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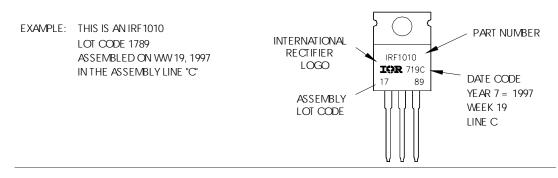
Package Outline TO-220AB

Dimensions are shown in millimeters (inches)



Part Marking Information TO-220AB

8



Data and specifications subject to change without notice. This product has been designed and qualified for the Automotive [Q101] market.

Qualification Standards can be found on IR's Web site.



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